

• General Description

The AGM30P25S combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

• Features

- Advance high cell density Trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance
- 100% Avalanche tested
- 100% DVDS tested

• Application

- MB/VGA Vcore
- SMPS 2nd Synchronous Rectifier
- POL application
- BLDC Motor driver

Product Summary

BVDSS	RDS(on)	ID
-30V	20mΩ	-8A

SOP8 Pin Configuration

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
AGM30P25S	AGM30P25S	SOP8	330mm	12mm	3000

Table 1. Absolute Maximum Ratings (TA=25°C)

Symbol	Parameter	Value	Unit
VDS	Drain-Source Voltage (VGS=0V)	-30	V
VGS	Gate-Source Voltage (VDS=0V)	±20	V
ID	Drain Current-Continuous(Tc=25°C) (Note 1)	-8.0	A
	Drain Current-Continuous(Tc=100°C)	-4.8	A
IDM (pluse)	Drain Current-Continuous@ Current-Pulsed (Note 2)	-32	A
PD	Maximum Power Dissipation(Tc=25°C)	2.5	w
	Maximum Power Dissipation(Tc=100°C)	1.0	w
EAS	Avalanche energy (Note 3)	72	mJ
TJ,TSTG	Operating Junction and Storage Temperature Range	-55 To 150	°C

Table 2. Thermal Characteristic

Symbol	Parameter	Typ	Max	Unit
R _{θJA}	Thermal Resistance Junction-ambient (Steady State) ¹	---	50	°C/W

Table 2. P-Channel Electrical Characteristics (TJ=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
On/Off States						
BVDSS	Drain-Source Breakdown Voltage	VGS=0V ID=-250μA	-30	--	--	V
IDSS	Zero Gate Voltage Drain Current	VDS=-30V, VGS=0V	--	--	-1	μA
IGSS	Gate-Body Leakage Current	VGS=±20V, VDS=0V	--	--	±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=-250μA	-1.2	-1.5	-2.2	V
gFS	Forward Transconductance	VDS=-5V, ID=-4A	--	7	--	S
RDS(on)	Drain-Source On-State Resistance	VGS=-10V, ID=-5A	--	20	28	mΩ
		VGS=-4.5V, ID=-4A	--	30	40	mΩ
Dynamic Characteristics						
Ciss	Input Capacitance	VDS=-15V, VGS=0V, F=1MHZ	--	652	--	pF
Coss	Output Capacitance		--	95	--	pF
Crss	Reverse Transfer Capacitance		--	85.7	--	pF
Switching Times						
td(on)	Turn-on Delay Time	VGS=-10V, VDS=-15V, ID=-4A, RGEN=3Ω, RL=3.6Ω	--	8.0	--	nS
tr	Turn-on Rise Time		--	4.0	--	nS
td(off)	Turn-Off Delay Time		--	26	--	nS
tf	Turn-Off Fall Time		--	12.5	--	nS
Qg	Total Gate Charge	VGS=-10V, VDS=-15V, ID=-1A	--	14	--	nC
Qgs	Gate-Source Charge		--	1.3	--	nC
Qgd	Gate-Drain Charge		--	3.0	--	nC
Source-Drain Diode Characteristics						
ISD	Source-Drain Current(Body Diode)		--	--	-8.0	A
VSD	Forward on Voltage	VGS=0V, IS=-5A	--	--	-1.2	V
trr	Reverse Recovery Time	IF=-5A, dI/dt=100A/μs, TJ=25°C	--	--	--	ns
Qrr	Reverse Recovery Charge		--	--	--	nc

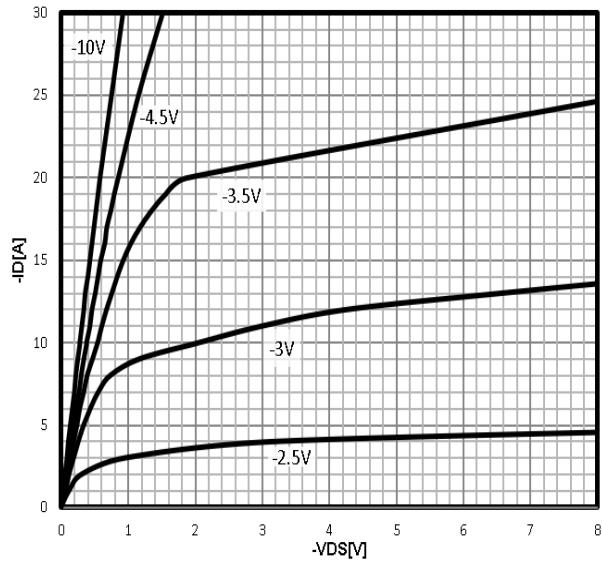
Notes 1.The maximum current rating is package limited.

Notes 2.Repetitive Rating: Pulsewidth limited by maximum junction temperature Notes

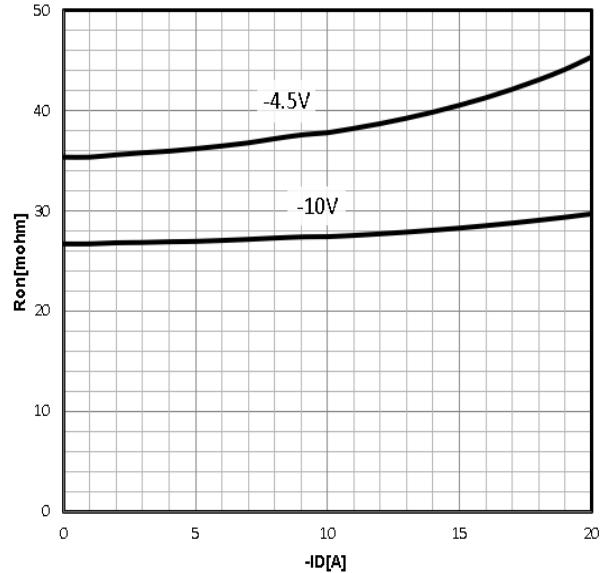
3.EAS condition: TJ=25°C, VDD=-15V, Vgs=-10V, ID=-17A, L=0.5mH, RG=25ohm

Characteristics Curve:

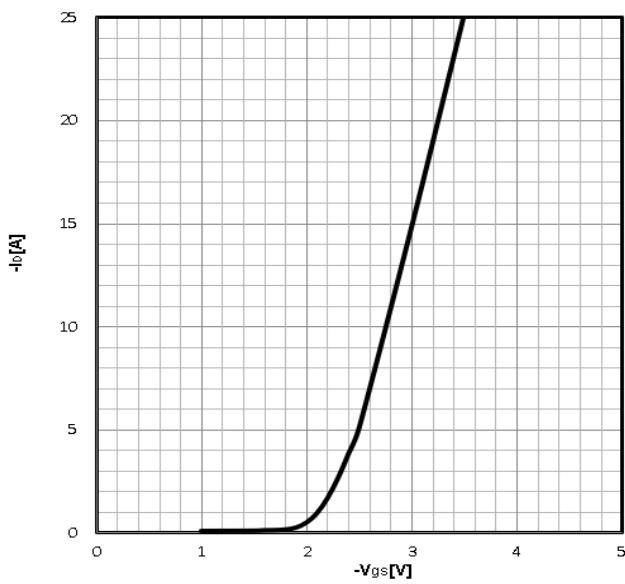
Typ. output characteristics
 $I_D = f(V_{DS})$



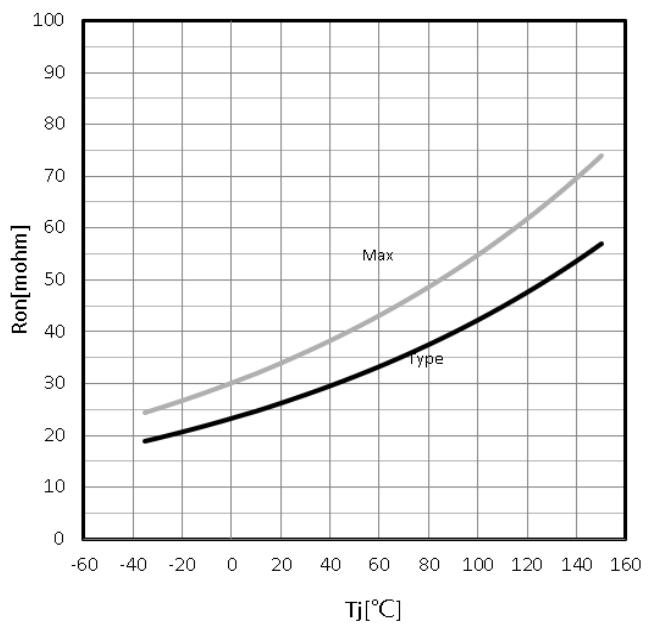
Typ. drain-source on resistance
 $R_{DS(on)} = f(I_D)$



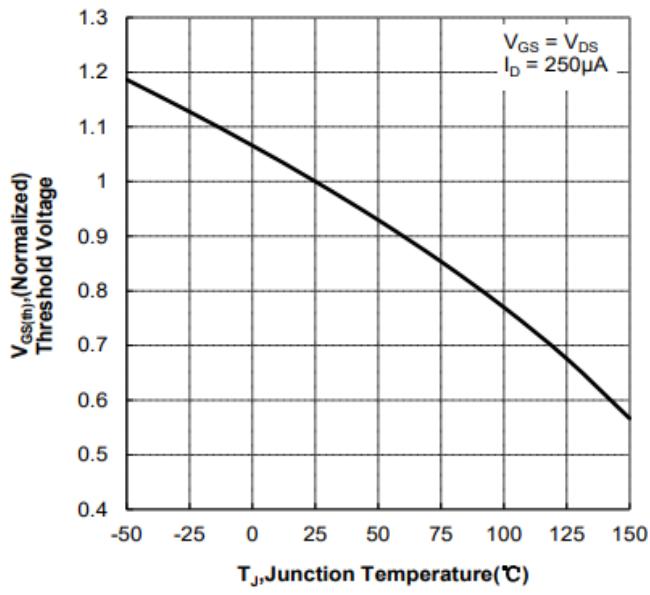
Typ. transfer characteristics
 $I_D = f(V_{GS})$



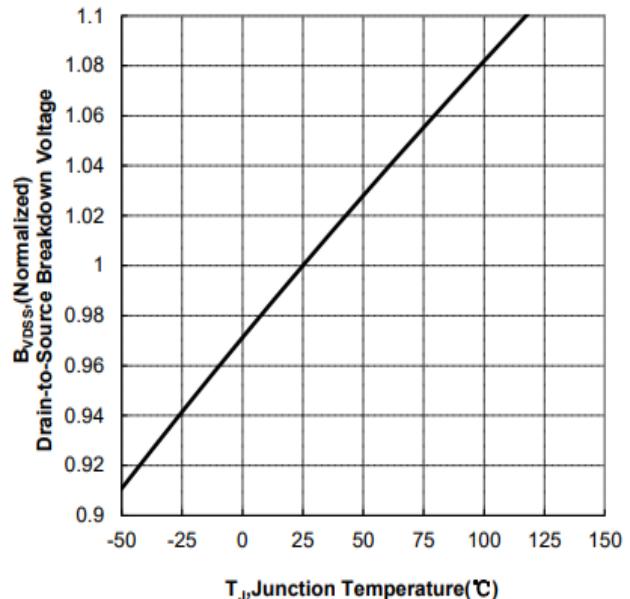
Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = -5A; V_{GS} = -10V$



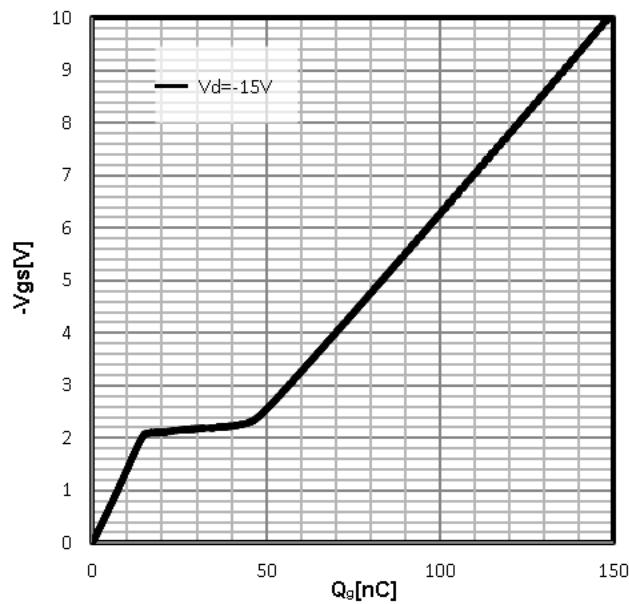
Gate Threshold Voltage
 $-V_{TH} = f(T_j)$; $I_D = -250\mu A$



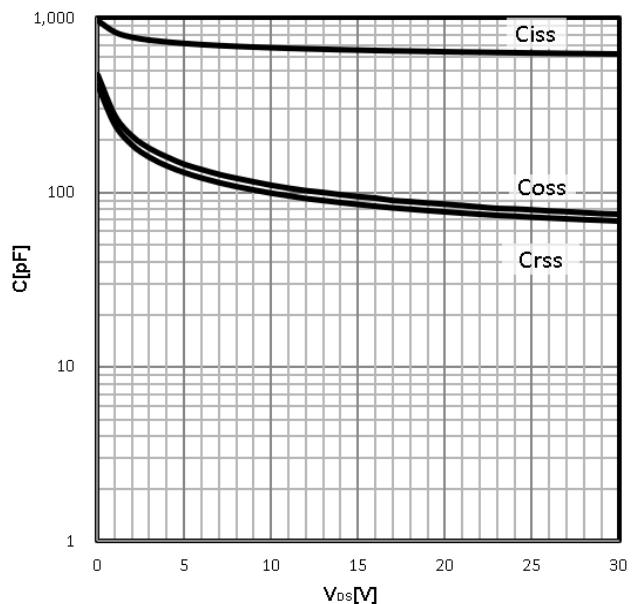
Drain-source breakdown voltage
 $V_{BR(DSS)} = f(T_j)$; $I_D = -250\mu A$



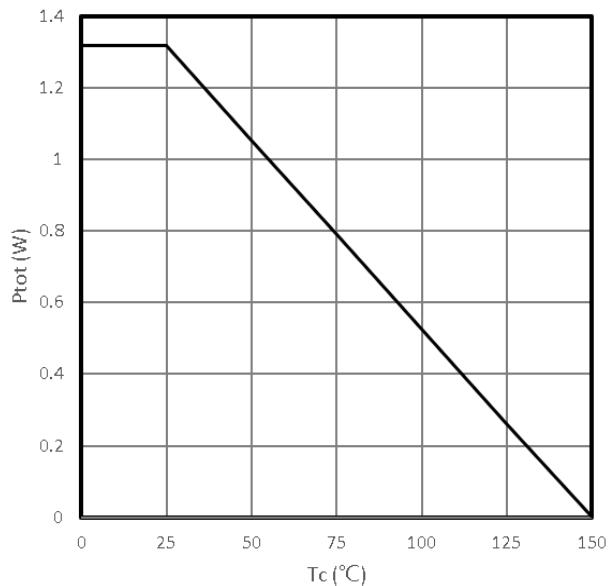
Typ. gate charge
 $V_{GS} = f(Q_{gate})$; $I_D = -1A$



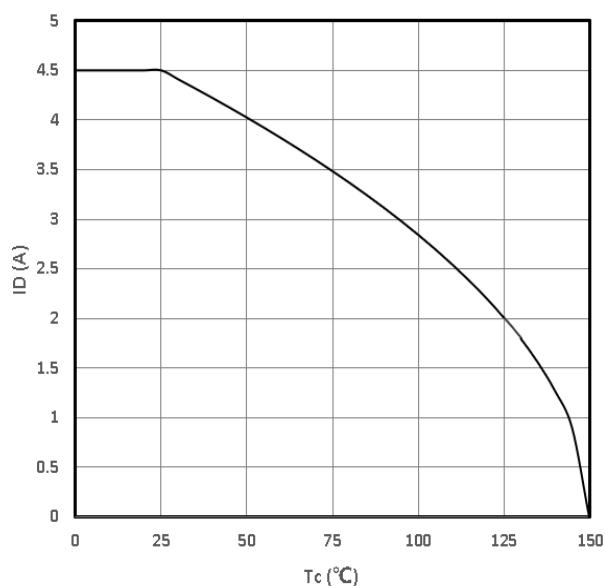
Typ. capacitances
 $C = f(V_{DS})$; $V_{GS} = 0V$; $f = 1MHz$



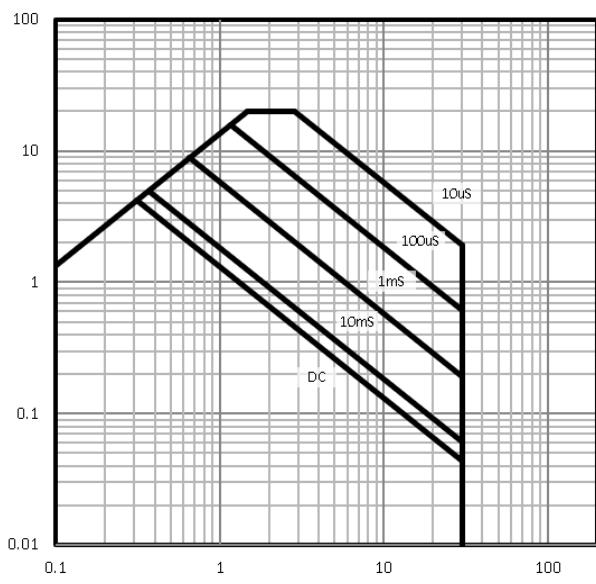
Power Dissipation
 $P_{tot}=f(T_C)$



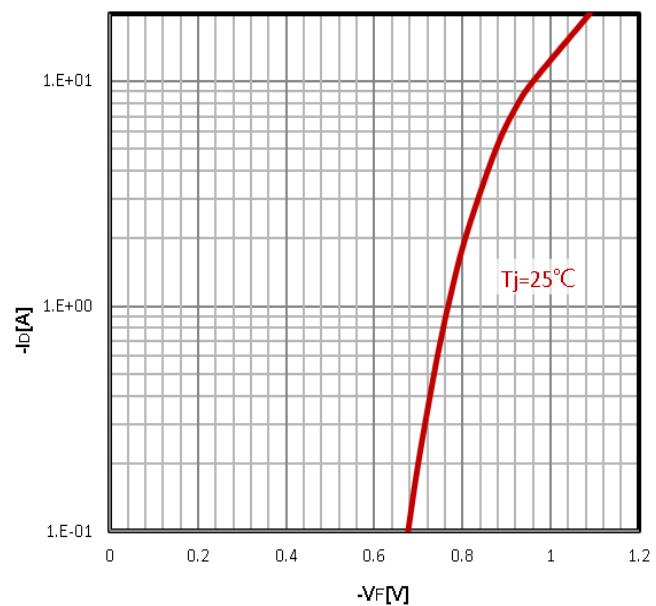
Maximum Drain Current
 $-I_D=f(T_C)$



Safe operating area
 $-I_D=f(-V_{DS})$

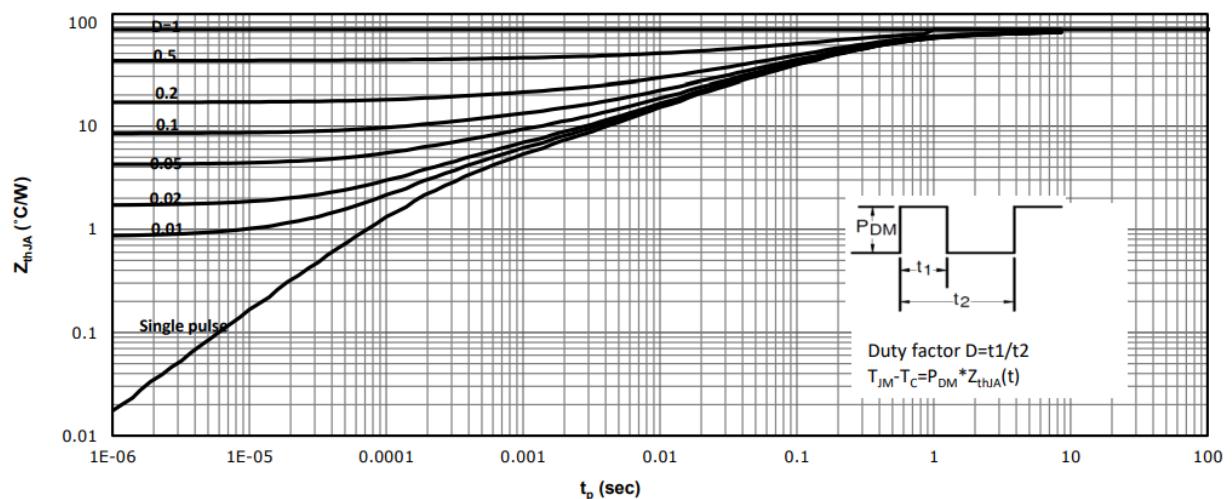


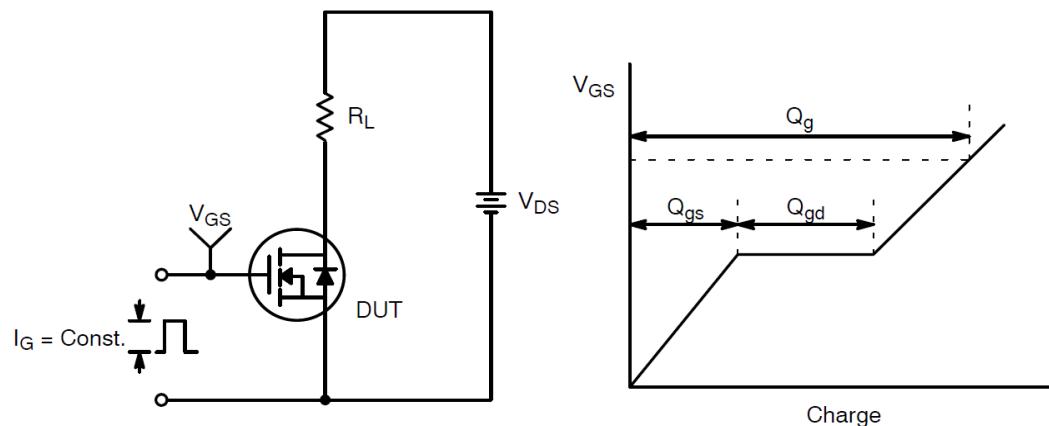
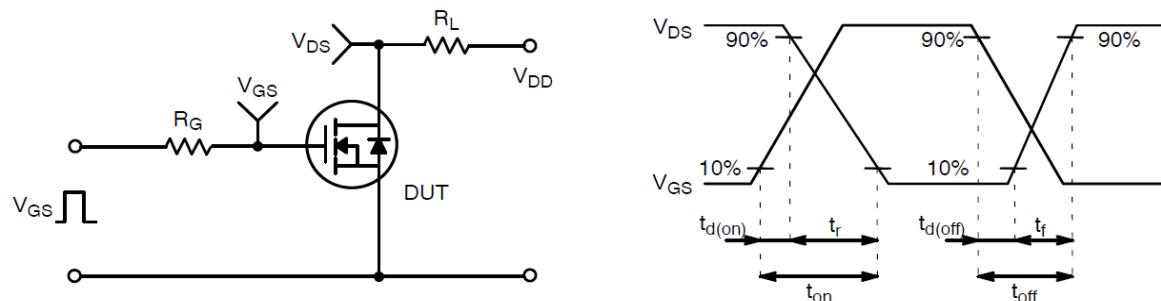
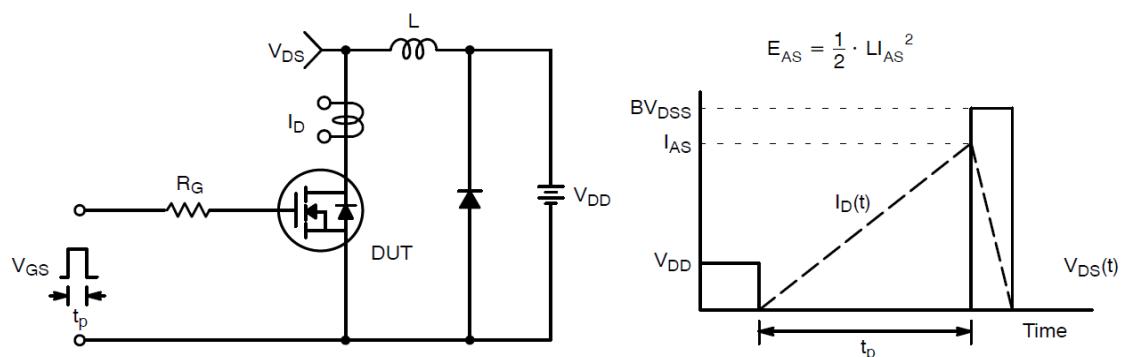
Body Diode Forward Voltage Variation
 $-I_F=f(-V_{DF})$



Max. transient thermal impedance

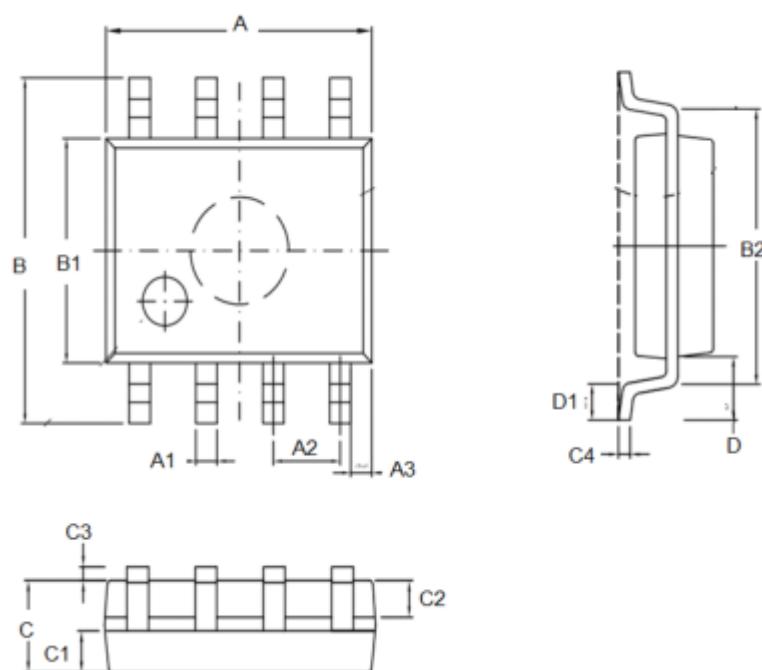
$$Z_{thJC} = f(t_p)$$



Test Circuit and Waveform:

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms

•Dimensions(SOP8)

SYMBOL	min	TYP	max	SYMBOL	min		max
A	4.80		5.00	C	1.30		1.50
A1	0.37		0.47	C1	0.55		0.75
A2		1.27		C2	0.55		0.65
A3		0.41		C3	0.05		0.20
B	5.80		6.20	C4	0.19	0.20	0.23
B1	3.80		4.00	D		1.05	
B2		5.00		D1	0.40		0.62



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